

# ISO 18114:2021 (E)

## Surface chemical analysis — Secondary-ion mass spectrometry — Determination of relative sensitivity factors from ion-implanted reference materials

---

### Contents

	Foreword
	Introduction
1	Scope
2	Normative references
3	Terms and definitions
4	Symbols and abbreviated terms
5	Principle
6	Apparatus
7	Ion-implanted reference materials
8	Procedure
9	Test report

Page count: 4